

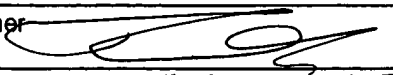
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary) PTO Form 1449	Attorney Docket No. 053785-5157	Serial No. Unassigned
	Applicants Young-Joo KIM	
	Filing Date November 21, 2003	Group Unassigned

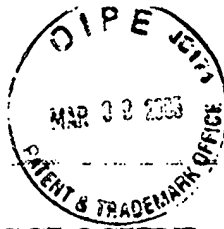
U.S. PATENT DOCUMENTS

*Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date

FOREIGN PATENT DOCUMENTS							
	Document Number	Date	Country	Class	Sub Class	Translation	
						YES	NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)		
TSP		H. IKEDA. "Evaluation of Grain Boundary Trap States in Polycrystalline-Silicon Thin-Film Transistors by Mobility and Capacitance Measurements." <u>Journal of Applied Physics</u> . Vol. 91, No. 7, April 2002, pp. 4637-4645.

Examiner: 	Date Considered: 11/29/03
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INFORMATION DISCLOSURE CITATION

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PTO Form 1449

Attorney Docket No.

053785-5157

Application No.

10/717,676

Applicant: Young-Joo KIM

Filing Date: November 21, 2003

Group Art Unit: Unassigned

U.S. PATENT DOCUMENTS

* Examiner Initial	Document Number	Date	Name	Class	Sub Class	Filing Date

FOREIGN PATENT DOCUMENTS

	Document Number	Date	Country	Class	Sub Class	Translation YES NO
TS8	2001-0087667	09/21/2001	Korea			Abstract
TS8	2001-0066251	07/11/2001	Korea			Abstract

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner

Date Considered

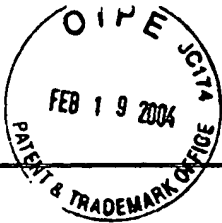
11/28/05

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March 9, 2005

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	Document Number	Date	Country	Class	Sub Class	<u>Translation</u> YES NO

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

TSP		Single-Crystal Si Films Via a Low-Substrate-Temperature Excimer-Laser Crystallization Method, R Sposili, et al. Mat. Res. Soc. Symp. Proc. Vol. 542, 956, pp 953-958.

Examiner		Date Considered	2/25/05
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February 19, 2004
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